

**Notice of References Cited**

Application/Control No.

09/714,154

Applicant(s)/Patent Under Reexam

Aokl

Examiner

David L Lewis

Art Unit

2673

Page 1 of 1

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	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Name</b>	<b>Classification<sup>2</sup></b>	
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**NON-PATENT DOCUMENTS**

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